



Advanced Management for 3bpc NAND Flash devices

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DensBits

Outline

- ECC for High Reliability 3bpc Embedded System
 - ECC Requirements
 - DensBits' solution
- Ungraceful power-down
 - Problem definition
 - Common solutions and DensBits' solution

ECC Requirements

- Powerful – Must correct many more errors
 - Powerful hard decoding
 - Powerful soft decoding
- Low latency – Must support higher throughput and IOPs
- Low power consumption – Embedded system requirement
- Low gate count

- **But: “Long BCH Codes are Bad”**, S. Lin & E. J> Weldon, Information & Control, 1967

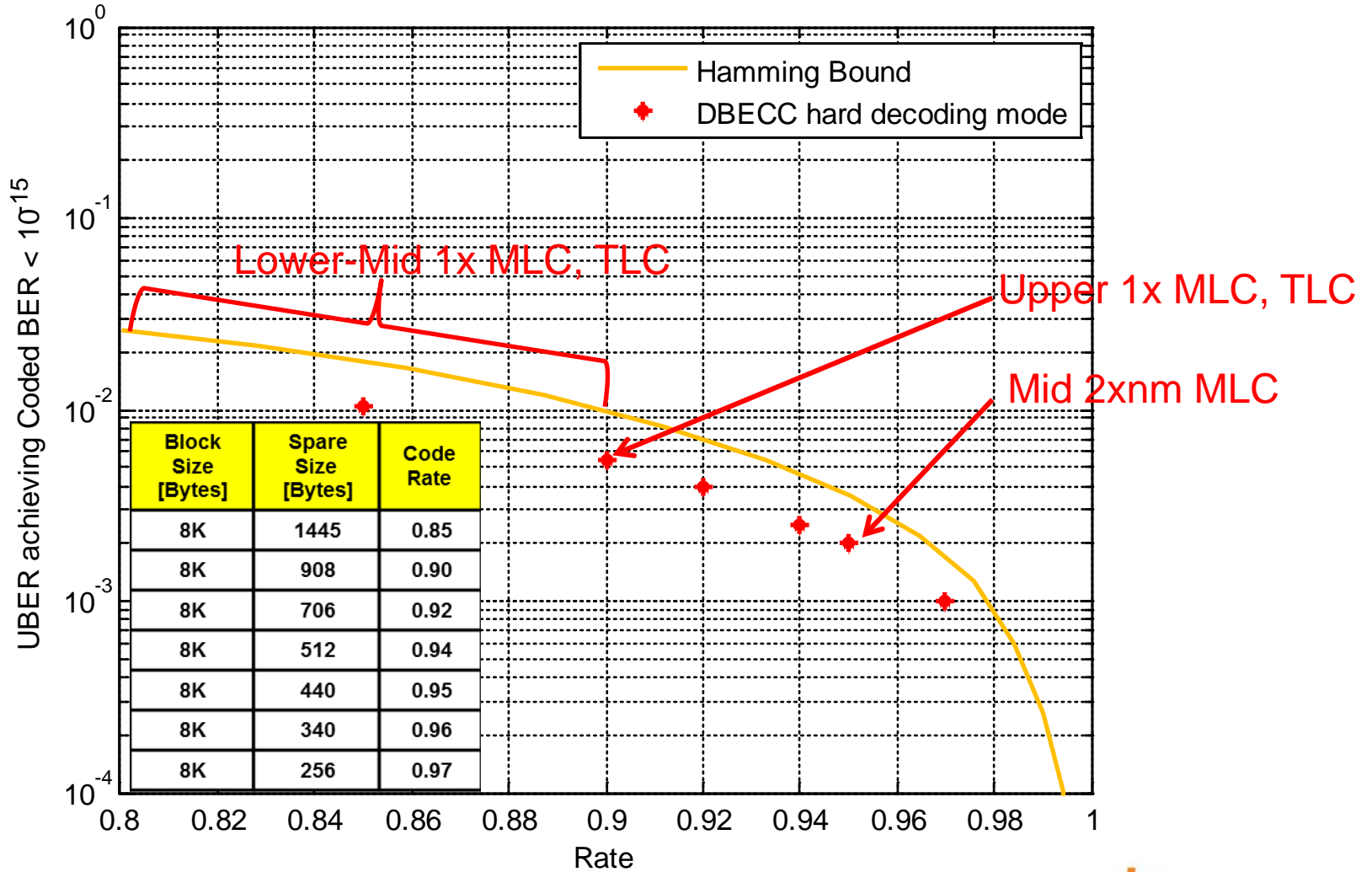
DensBits' ECC

- DensBits' **proprietary, patent pending** coding system (not LDPC nor BCH)
- **Configurable coding system**, the chunk size and code rate are input parameters set via software
 - Chunk size: 512B-8KB
 - Code rate: 0.5 - 0.99
- **Slim design / low power**: 380KG / 7.5mA (65nm, 100MHz Clock)
- **Near-optimal error correction** per chunk size
 - Near Hamming bound (theoretical limit for hard decoding)
 - Near Shannon bound (theoretical limit for soft decoding)

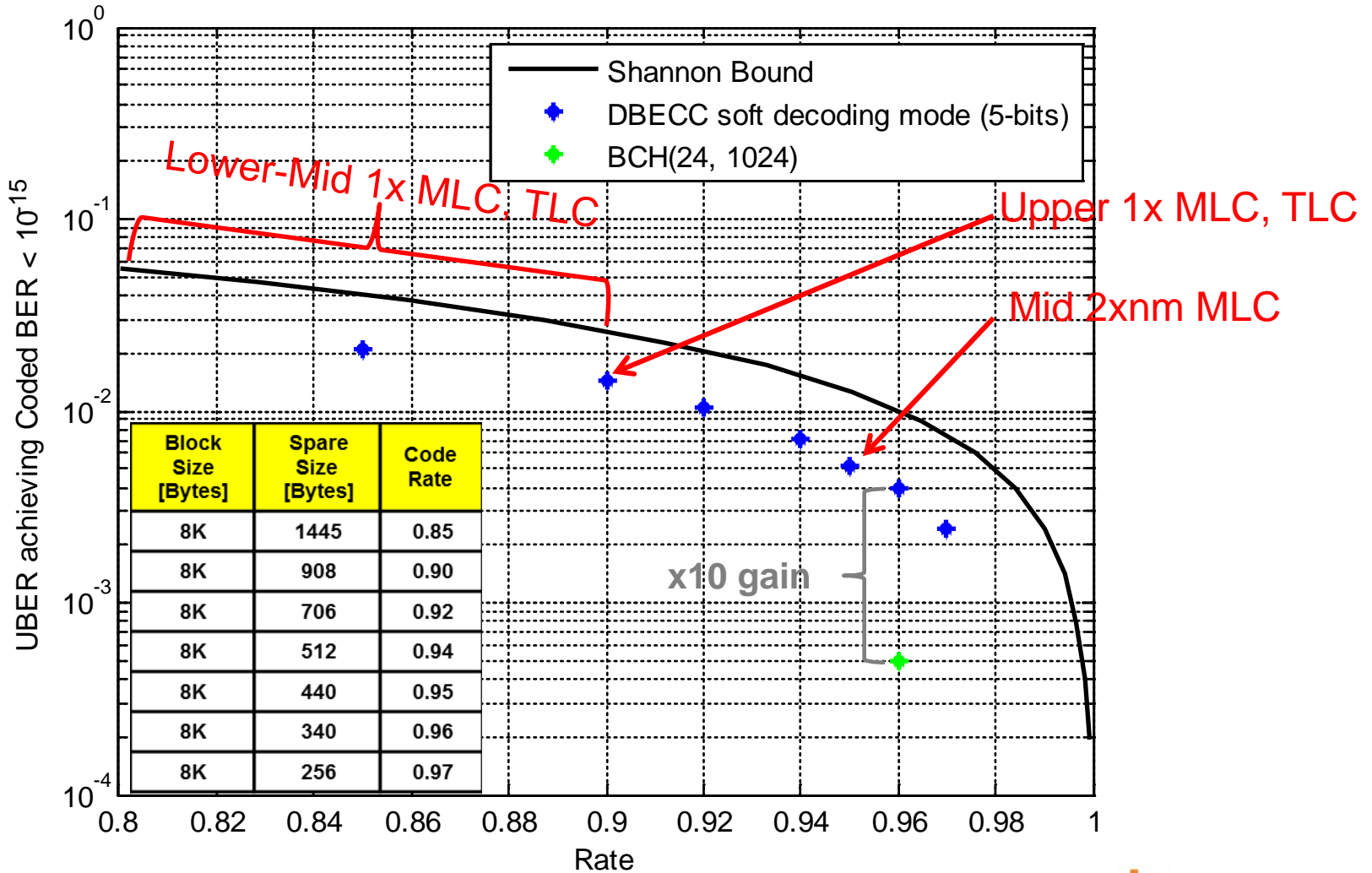
DensBits' ECC (Cont.)

- Partial decoding support, enabling **low read latency**
 - Decode 1 or 2 KB out of an 4 or 8 KB codeword
 - Improved read performance, e.g., **high IOPs** for SSD / eMMC

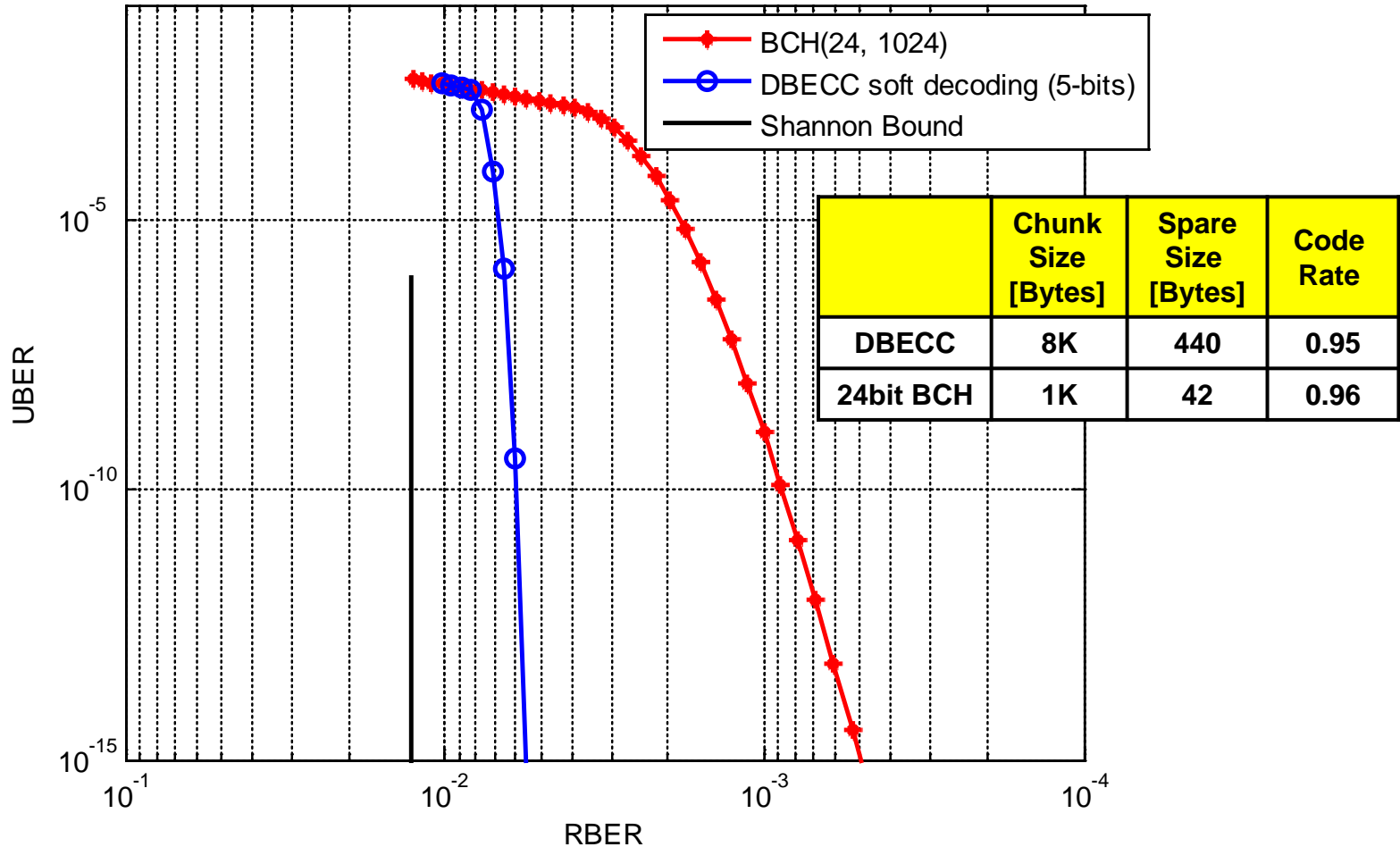
ECC (Cont.)



ECC (Cont.)



ECC (Cont.)



ECC (Cont.)

- Examples for several chunk sizes and code rates

Code Rate		RBER @ UBER<1E-15			
		Chunk Size			Shannon Limit
		2KB	4KB	8KB	
0.9	DBECC Hard / Hamming Bound	4E-3 / 7.8E-3	5.2E-3 / 9.1E-3	5.5E-3 / 1E-2	
	DBECC Soft	9.5E-3	1.2E-2	1.4E-2	2.6E-2
0.95	DBECC Hard / Hamming Bound	8E-4 / 2.5E-3	1.3E-3 / 3.1E-3	2E-3 / 3.8E-3	
	DBECC Soft	3.6E-3	4.4E-3	5.3E-3	1.3E-2

ECC (Cont.)

	Hardware Implementation	
Manufacturing Process	65nm	65nm
Clock	100MHz	100MHz
Throughput	100MB/s	400MB/s
Latency	4us	4us
Power Consumption (inc. external buffers)	7.5mA	30mA
Gate Count	380KG	700KG

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 - **Problem definition**
 - **Common solutions and DensBits' solution**

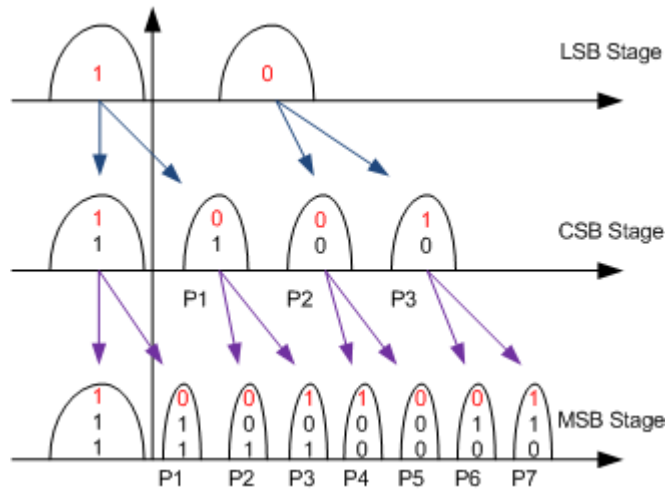
Power down scenarios

- Managed power off
 - Required data-bases are stored prior to power down
- Sudden power off between transactions (graceful power off)
 - All written data are recoverable through meta-data
- Sudden power off within a write transaction (Ungraceful power loss)
 - All data except for last (interrupted) transaction must be recovered
 - **Past data may be damaged due to interruption**

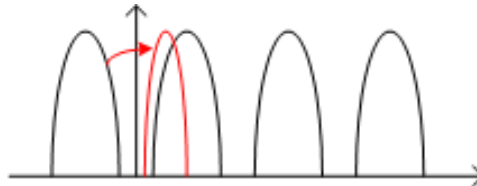
Ungraceful power loss

- Unfinished programming may destroy past data:

- Normal Programming procedure:



- Interrupted programming:



Ungraceful power off (Cont.)

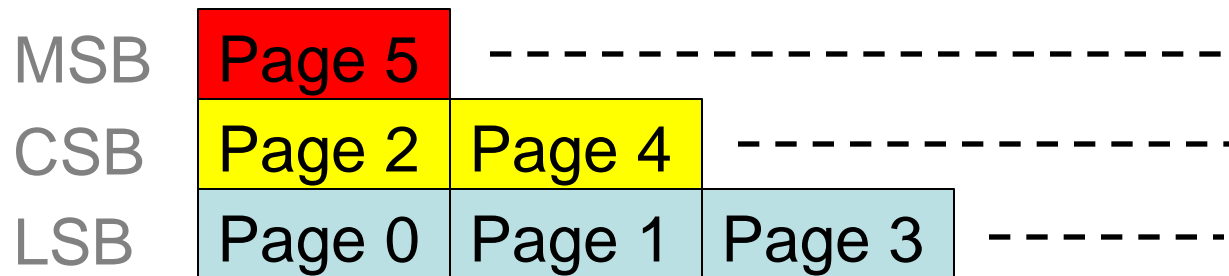
- Page programming order:

LSB	CSB	MSB
0	2	5
1	4	8
3	7	11
6	10	14
9	13	15

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Ungraceful power off (Cont.)

- Interrupted CSB page programming may damage lower LSB page
- Interrupted MSB page programming may damage lower LSB and CSB pages



Ungraceful power loss (Cont.)

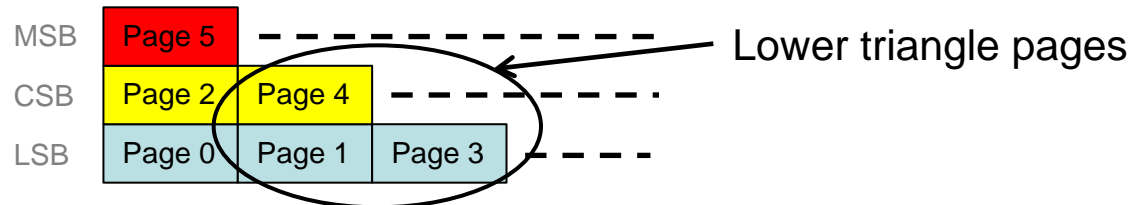
- Existing solutions:
 - I. Soldered battery preventing ungraceful power-downs
 - ☛ Not applicable if battery is replaceable
 - II. Use a super-cap that holds VDD until current page programming operation completes
 - ☛ Added cost
 - ☛ Form factor may not allow insertion of super-cap

Ungraceful power loss (Cont.)

- Existing solutions:

III. Recover past data prior to last interrupted transaction using stored backup data:

1. Allocate a data “backup” block
2. Pre/Post page programming operation: pages belonging to the lower triangle are “backed up”



👉 Performance impact due to backup operation. Impact highest during short transactions

IV. DensBits solution uses a proprietary backup solution whose performance impact is less than 5%



Thank You